

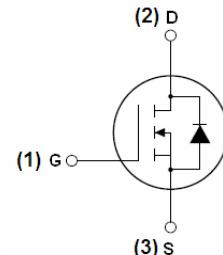
60V N-Channel MOSFET

Description

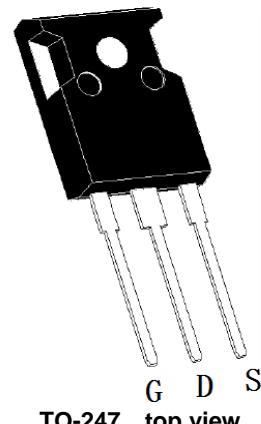
The FNK 3206T uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in automotive applications and a wide variety of other applications.

Features

- $V_{DS}=60V$; $I_D=210A @ V_{GS}=10V$;
 $R_{DS(ON)} < 3m\Omega @ V_{GS}=10V$
- High density cell design for ultra low $R_{DS(on)}$
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation



Schematic diagram



TO-247 top view

Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply

Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted				
Parameter	Symbol	Maximum	Units	
Drain-Source Voltage	V_{DS}	60	V	
Gate-Source Voltage	V_{GS}	± 20	V	
Continuous Drain Current ^G	I_D	210	A	
$T_C=100^\circ C$		160		
Pulsed Drain Current ^C	I_{DM}	840		
Continuous Drain Current ^A	I_{DSM}	18	A	
$T_A=70^\circ C$		15		
Avalanche Current ^C	I_{AS}, I_{AR}	108	A	
Avalanche energy $L=0.3mH^C$	E_{AS}, E_{AR}	874	mJ	
Power Dissipation ^B	P_D	333	W	
$T_C=100^\circ C$		167		
Power Dissipation ^A	P_{DSM}	1.9	W	
$T_A=70^\circ C$		1.2		
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 175	°C	

Thermal Characteristics				
Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$t \leq 10s$	R_{0JA}	12	$^\circ C/W$
Maximum Junction-to-Ambient ^{A D}	Steady-State		54	$^\circ C/W$
Maximum Junction-to-Case	Steady-State	R_{0JC}	0.35	$^\circ C/W$

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	60			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=60\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS} = \pm 25\text{V}$			100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	2.2	2.9	4	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	540			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$ $T_J=125^\circ\text{C}$		2.2 2.8	3 4	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$		60		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.67	1	V
I_S	Maximum Body-Diode Continuous Current ^G				180	A
DYNAMIC PARAMETERS						
C	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=30\text{V}, f=1\text{MHz}$	7750			pF
C	Output Capacitance		1370			pF
C	Reverse Transfer Capacitance		900			pF
R	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	1.37			Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=30\text{V}, I_D=20\text{A}$	85	108	130	nC
Q_{gs}	Gate Source Charge		24	30	36	nC
Q_{gd}	Gate Drain Charge		27	46	65	nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=30\text{V}, R_L=1.5\Omega, R_{\text{GEN}}=3\Omega$		31		ns
t_r	Turn-On Rise Time			29		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			41		ns
t_f	Turn-Off Fall Time			13		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=20\text{A}, dI/dt=500\text{A}/\mu\text{s}$	20	35	50	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, dI/dt=500\text{A}/\mu\text{s}$	190	273	355	nC

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, $t \leq 10$ sec.
3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.
4. Guaranteed by design, not subject to production
5. EAS condition: $T_J=25^\circ\text{C}, V_{DD}=30\text{V}, V_G=10\text{V}, L=0.5\text{mH}, R_g=25\Omega$

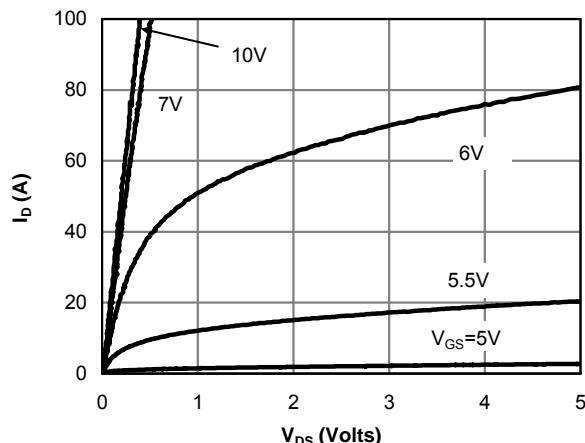
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Fig 1: On-Region Characteristics (Note E)

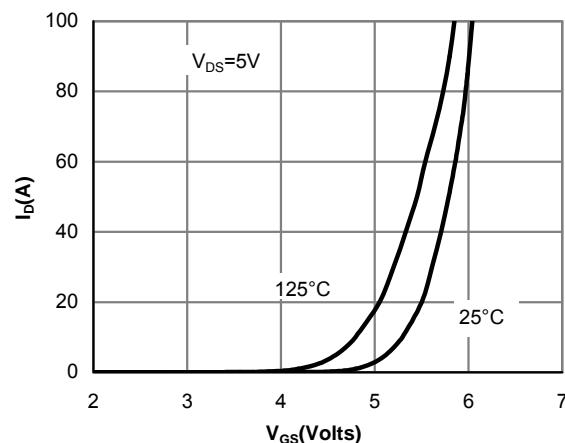


Figure 2: Transfer Characteristics (Note E)

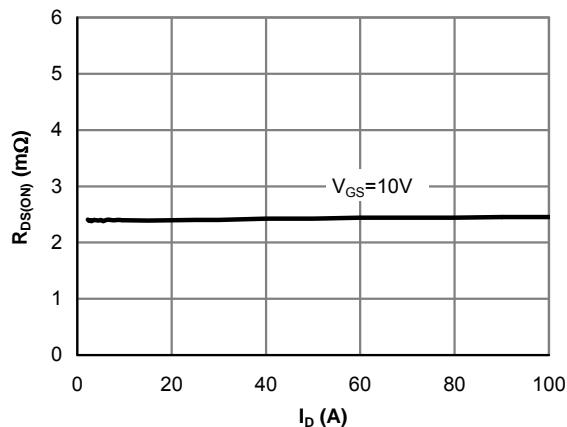


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

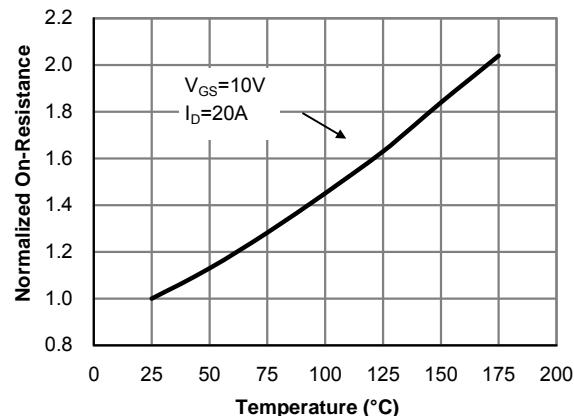


Figure 4: On-Resistance vs. Junction Temperature (Note E)

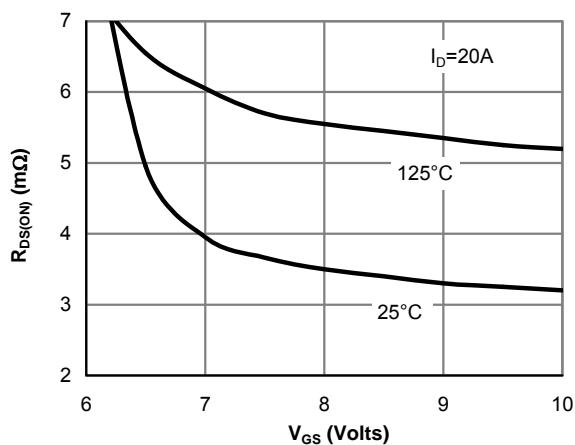


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

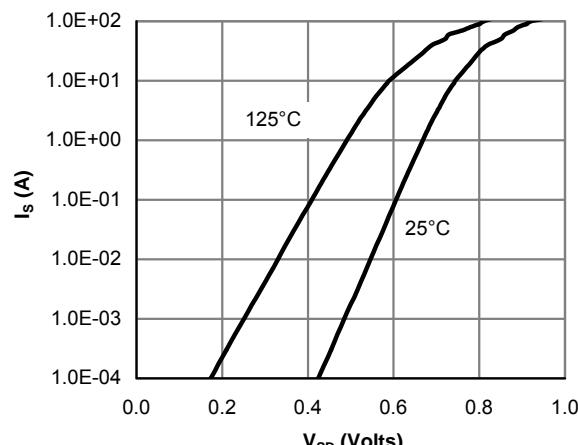


Figure 6: Body-Diode Characteristics (Note E)

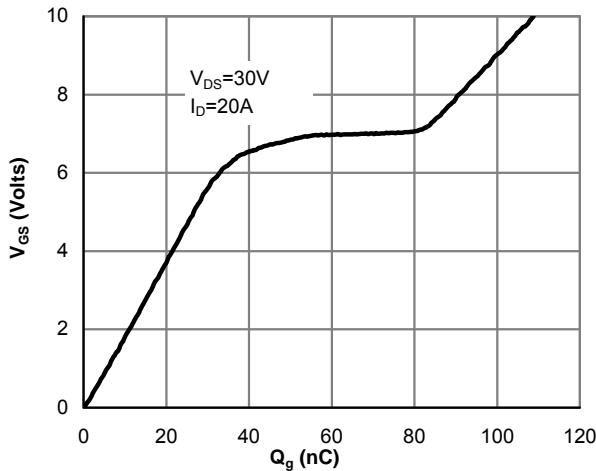
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Figure 7: Gate-Charge Characteristics

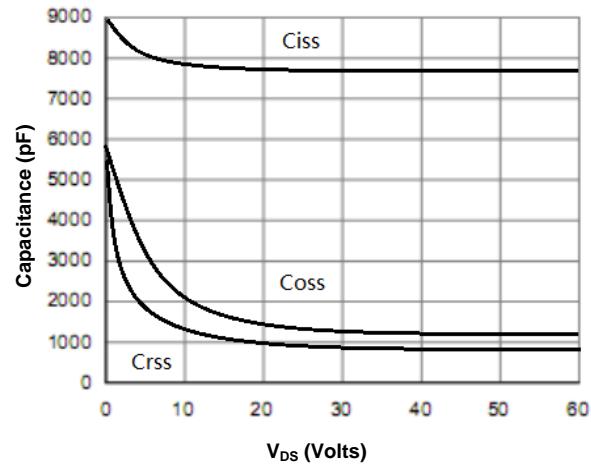


Figure 8: Capacitance Characteristics

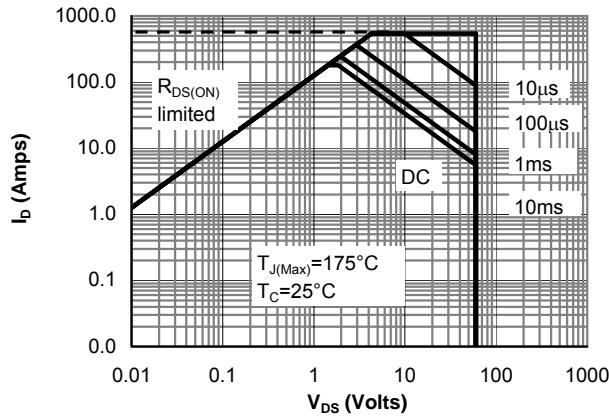


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

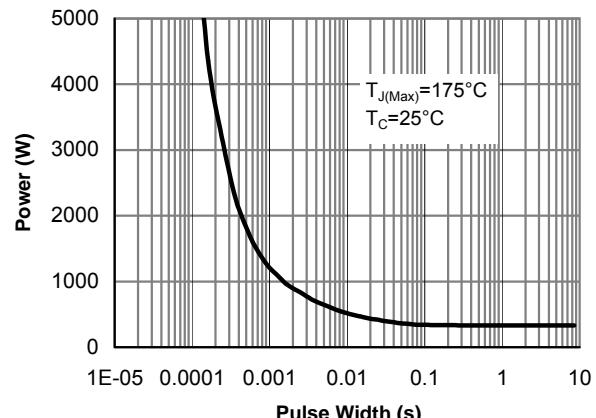


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

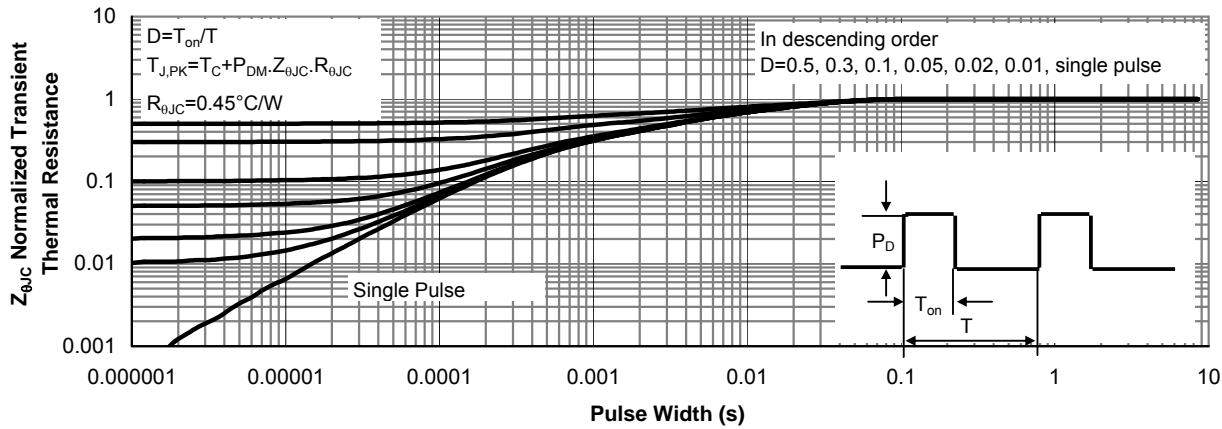


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

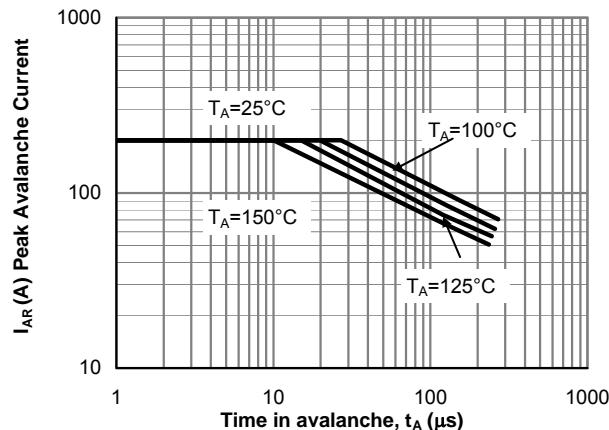
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Figure 12: Single Pulse Avalanche capability
(Note C)

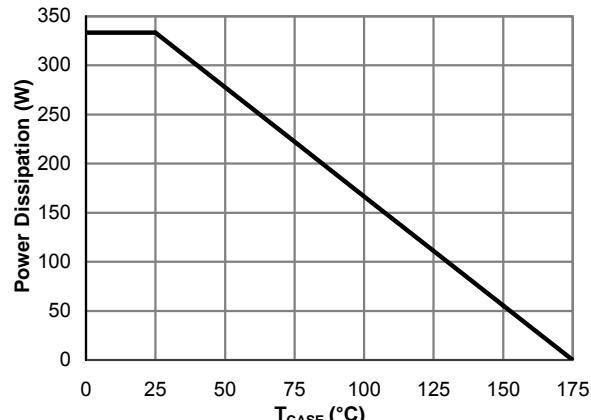


Figure 13: Power De-rating (Note F)

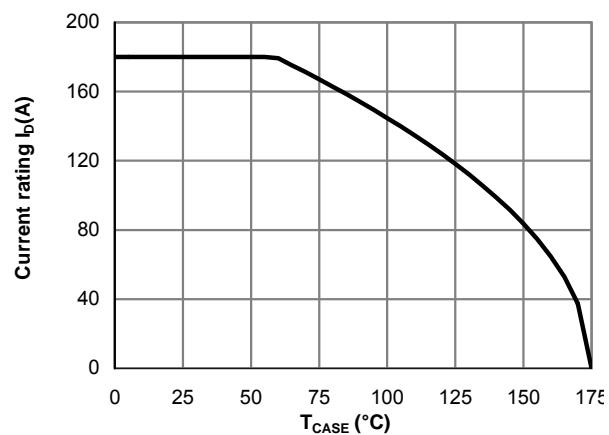


Figure 14: Current De-rating (Note F)

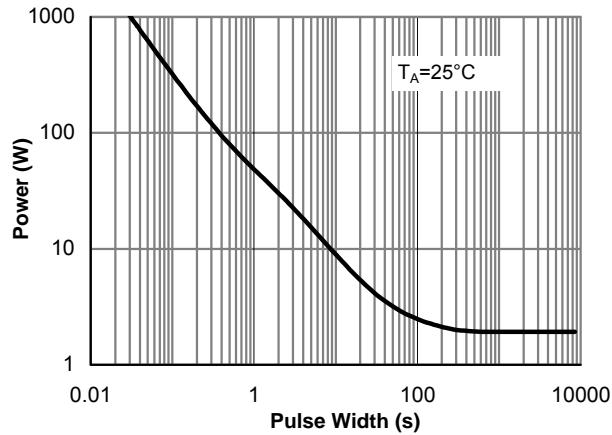


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note H)

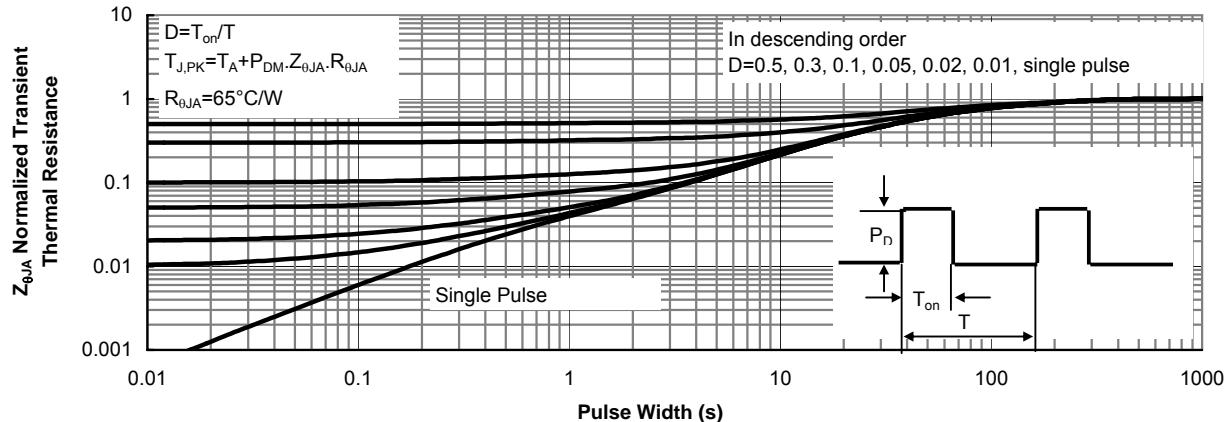
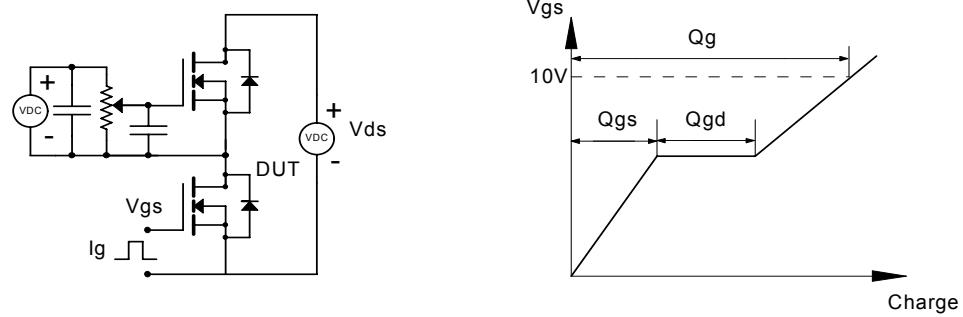
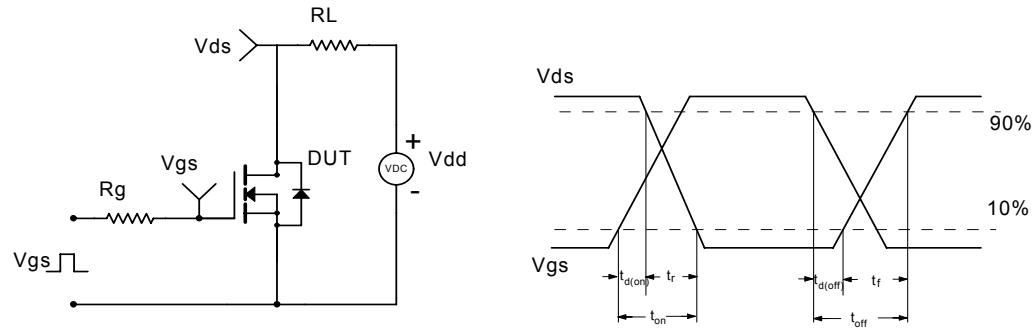


Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)

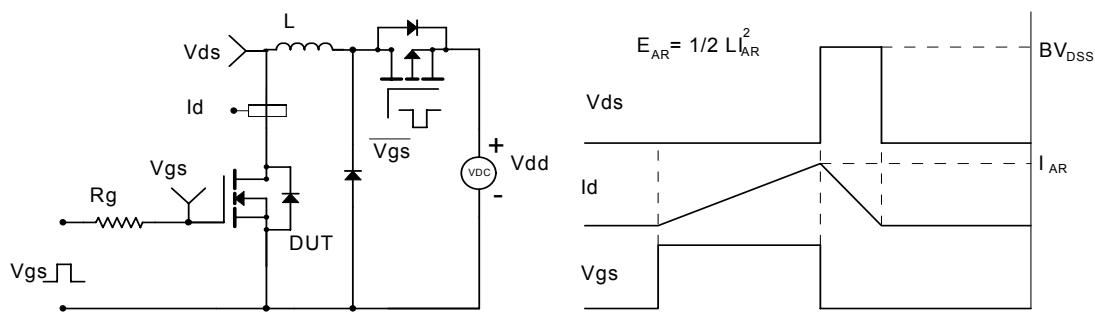
Gate Charge Test Circuit & Waveform



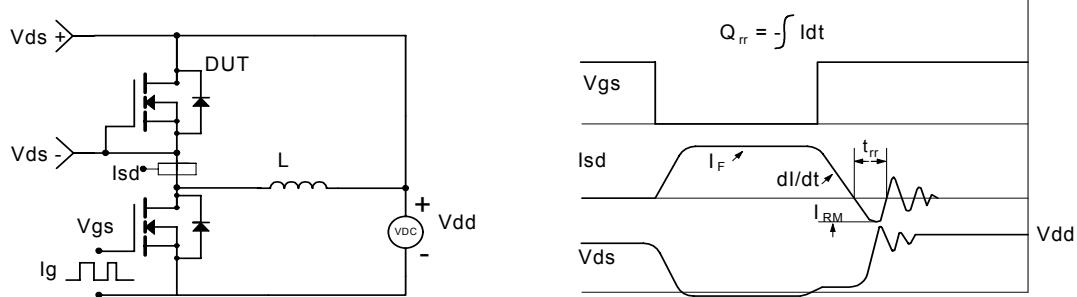
Resistive Switching Test Circuit & Waveforms

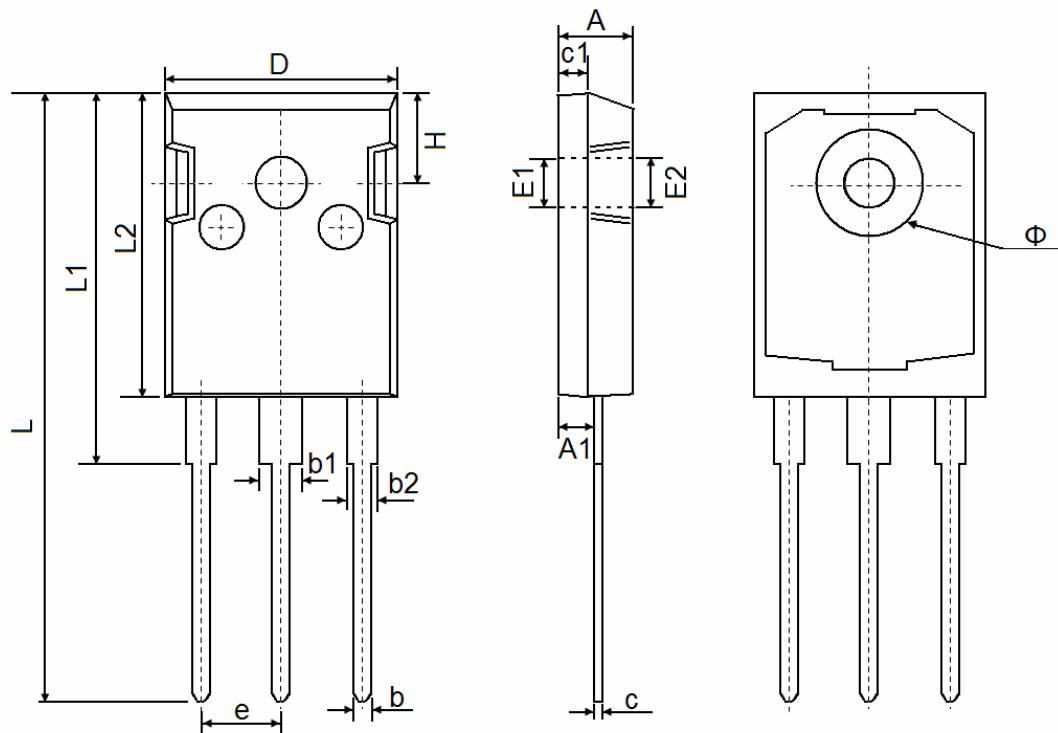


Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



TO-247 Package Information


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.850	5.150	0.191	0.200
A1	2.200	2.600	0.087	0.102
b	1.000	1.400	0.039	0.055
b1	2.800	3.200	0.110	0.126
b2	1.800	2.200	0.071	0.087
c	0.500	0.700	0.020	0.028
c1	1.900	2.100	0.075	0.083
D	15.450	15.750	0.608	0.620
E1	3.500 REF		0.138 REF	
E2	3.600 REF		0.142 REF	
L	40.900	41.300	1.610	1.626
L1	24.800	25.100	0.976	0.988
L2	20.300	20.600	0.799	0.811
Φ	7.100	7.300	0.280	0.287
e	5.450 TYP		0.215 TYP	
H	5.980 REF		0.235 REF	

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